


<b>Search Notes</b>  	<b>Application/Control No.</b>  10551817	<b>Applicant(s)/Patent Under Reexamination</b>  LIN ET AL.
	<b>Examiner</b>  Cheng, Ichieh	<b>Art Unit</b>  4183

SEARCHED			
Class	Subclass	Date	Examiner
455	560,442,449,552.1,331,440,437,456.1.445,438,439	10/10/2007	Ichieh Cheng
370	349,338,329,412,389,469,395.2,236,428,351,436,395.21,401	10/10/2007	Ichieh Cheng

SEARCH NOTES		
Search Notes	Date	Examiner
Text search attached	10/10/2007	Ichieh Cheng

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner